# 2SA2004

## Silicon PNP epitaxial planar type

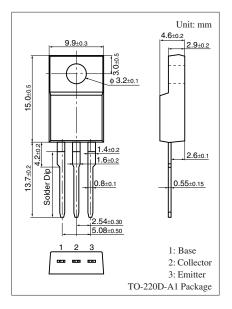
#### For power amplification

#### ■ Features

- High forward current transfer ratio h<sub>FE</sub>
- $\bullet$  Satisfactory linearity of forward current transfer ratio  $h_{\text{FE}}$
- Dielectric breakdown voltage of the package: > 5 kV
- High-speed switching

### ■ Absolute Maximum Ratings $T_a = 25$ °C

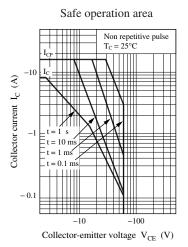
Parameter		Symbol	Rating	Unit	
Collector-base voltage (Emitter open)		V <sub>CBO</sub>	-60	V	
Collector-emitter voltage (Base open)		V <sub>CEO</sub>	-60	V	
Emitter-base voltage (Collector open)		$V_{EBO}$	-5	V	
Collector current		$I_C$	-8	A	
Peak collector current		$I_{CP}$	-16	A	
Collector power $T_C =$	25°C	P <sub>C</sub>	20	W	
dissipation			2.0		
Junction temperature		$T_{j}$	150	°C	
Storage temperature		T <sub>stg</sub>	-55 to +150	°C	

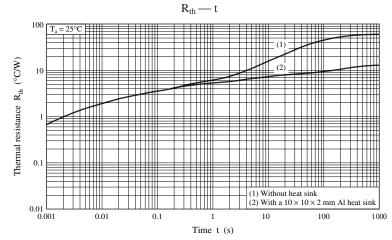


### ■ Electrical Characteristics $T_a = 25$ °C $\pm 3$ °C

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	$I_C = -10 \text{ mA}, I_B = 0$	-60			V
Collector-base cutoff current (Emitter open)	$I_{CBO}$	$V_{CB} = -60 \text{ V}, I_E = 0$			-100	μΑ
Collector-emitter cutoff current (Base open)	$I_{CEO}$	$V_{CE} = -60 \text{ V}, I_B = 0$			-100	μΑ
Forward current transfer ratio	h <sub>FE1</sub>	$V_{CE} = -2V, I_{C} = -0.1 A$	100		230	_
	h <sub>FE2</sub>	$V_{CE} = -2 \text{ V}, I_{C} = -5 \text{ V}$	30			
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	$I_C = -5 \text{ A}, I_B = -0.25 \text{ A}$			-1.2	V
Base-emitter saturation voltage	V <sub>BE(sat)</sub>	$I_C = -5 \text{ A}, I_B = -0.25 \text{ A}$			-1.7	V
Turn-on time	t <sub>on</sub>	$I_C = -4 A$		0.2	0.5	μs
Storage temperature	t <sub>stg</sub>	$I_{B1} = -400 \text{ mA}, I_{B2} = 400 \text{ mA}$		0.10	0.15	μs
Fall time	t <sub>f</sub>	$V_{CC} = -50 \text{ V}$		0.5	1.0	μs

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.





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